1FW

Docket No.: PEK-In1163

I hereby certify that this correspondent is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope and the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date indicated below.

Date: August 10, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No.

10/751,316

Confirmation No: 1985

Applicant

Wilhelm Asam et al.

Filed

January 2, 2004

Title

Method for Detecting the Reliability of Integrated Semiconductor

Components at High Temperatures

Art Unit

2826

Examiner

Scott R. Wilson

Docket No.

PEK-In1163 D

Customer No.:

24131

Letter under 37 C.F.R. §1.312

Hon. Commissioner for Patents

Sir:

In the IDS filed on January 2, 2004 German Patent DE 198 41 202 C1 (Gärtner et al.), dated March 2, 2000 was cited. The patent had been originally submitted in an IDS in parent application 10/200,934 on August 16, 2002. Inadvertently, this German patent was not listed on Form PTO-1449.

Applicants are submitting herewith a copy of German Patent DE 198 41 202 C1, corresponding U.S. Patent No. 6,255,892 B1 and Form PTO-1449.

Applicants kindly request that the Examiner consider this reference.

Respectfully submitted,

For Applicants

WERNER H. STEMER REG. NO. 34,956

Date: August 10, 2004

Lerner And Greenberg, P.A. Post Office Box 2480 Hollywood, FL 33022-2480

Tel: (954) 925-1100 Fax: (954) 925-1101

/bmb

			•					
		0	IPE			Sh	eet 1	of 1
FORM PTO-14	49 (SL	JBSTITUTE	Attorney Docket No.: Applic. No.					
U.S. DEPARTMENT OF COMMERCE AUG 1 3 2004 D 10/751,316								
PATENT AND TRADEMARK OFFICE Applicant								
INFO	RMAT	ON DISCLOSURE	Wilhelm Asam et al.					
STATEMENT BY APPLICANT (37 CFR 1.98(b))				Filing Date Group Art Unit				
				January 2, 2004 2826				
			!					
		U.S.	PATENT D	DOCUMENTS				
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILI DA	
INITIALS	Α	6,255,892 B1	07/03/01	Gärtner et al.	CLASS	CLASS		<u></u>
	В	, ,						
	С			100. 100. 100. 100. 100. 100.				
	D						<u> </u>	
	E							
	F							
	G							
	Н					<u> </u>		
	· ·							
	ł .		1		<u> </u>	I		
		FOREIG	GN PATEN	NT DOCUMENT				
				001117711	0, 400	SUB	TRAI	
	J	DOCUMENT NO. 198 41 202 C1	03/02/00	COUNTRY Germany	CLASS	CLASS	YES	NO
	K	198 41 202 01	03/02/00	Germany				
	L							
	М							
	N		<u> </u>			L	<u> </u>	İ
отн	ER DO	OCUMENTS (Inclu	uding Auth	or, Title, Date, Pe	rtinent Pa	ages, etc.)	
	0							
	Р							
	'							

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

EXAMINER

DATE CONSIDERED